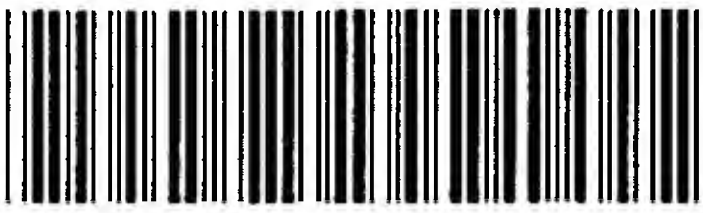


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,062	CHEN ET AL.	
	Examiner	Art Unit	
	Nhan T. Tran	2622	

SEARCHED			
Class	Subclass	Date	Examiner
348	222.1	10/15/2007	NT
348	231.99	10/16/2007	NT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	10/15/2007	NT
348/231.1-231.99 (text search - see search history printout)	10/16/2007	NT
348/211.1-211.14 (text search - see search history printout)	12/7/2007	NT